

## TECHNICAL ARTICLE

# Oxford Instruments Xplore 30: EDS analysis in SEM

Oxford Instruments Xplore 30: EDS analysis in SEM - LeakLab solutions for leak testing, vacuum systems and test equipment.

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## Technical and Project Information

This technical overview covers Oxford Instruments Xplore 30: EDS analysis in SEM. It is retained for technical context; specifications, availability, dates, commercial terms, and compliance statements must be reconfirmed for every current project.

### International project context

For a current application, specifications and availability must be checked against the exact equipment configuration, destination country, operating conditions, and required standards. Legacy announcements do not constitute a current quotation or compliance statement.

### Discuss your application

Send the test object, process conditions, target sensitivity or vacuum range, acceptance criteria, quantity, and schedule. LeakLab will review the information and confirm a suitable technical route.

## WORLDWIDE PROJECT CONTACT

Send the test object or system, operating conditions, target sensitivity or pressure range, applicable standard, destination country, quantity and schedule. LeakLab will review the project scope.

[mail@leaklab.org](mailto:mail@leaklab.org)

Regarding: Oxford Instruments Xplore 30: EDS analysis in SEM

Specifications, standards, verification scope, availability and commercial terms must be confirmed for the exact configuration and destination jurisdiction before order or project acceptance.